

PACS: 68.37.Lp, 68.37.Hk, 61.05.jm, 61.46.Df, 25.40.Dn, 25.40.Fq, 28.20.Fc

## EDP STUDY OF NANOCRYSTALLINE SILICON CARBIDE (3C-SiC) UNDER THE NEUTRON IRRADIATION

E.M. Huseynov

*Institute of Radiation Problems of ANAS*

[elchin.h@yahoo.com](mailto:elchin.h@yahoo.com)

**Abstract:** In this present work nanocrystalline silicon carbide (3C-SiC) has been irradiated with neutron flux ( $\sim 2 \times 10^{13} \text{ n} \cdot \text{cm}^{-2} \cdot \text{s}^{-1}$ ) up to 20 hour at different periods. Electron diffraction patterns (EDP) investigation of nanocrystalline 3C-SiC particles ( $\sim 18 \text{ nm}$ ) is comparatively analyzed before and after neutron irradiation. The effect of irradiation on the crystal structure of the nanomaterial was studied by selected area electron diffraction (SAED) and EDP analysis. Amorphous transformation effects of neutron irradiation on the nanocrystalline silicon carbide (3C-SiC) has been studied by EDP method.

**Key words:** nanocrystalline 3C-SiC, nanoparticles, neutron irradiation, TEM, FE-SEM

### 1. Introduction

Over the past few years, obtaining new materials or reprocessing current materials in the nuclear and cosmic technologies have been at the focus of various studies worldwide. SiC is an attractive material that can be applied in nuclear technologies due to the physical and chemical properties [1-5]. High temperature resistance, high-perfection structure, mechanical stability, high oxidation resistance increase the application potential of SiC as a nuclear material [2-4]. The combination of perfect mechanical and functional properties is the basis of application of SiC as a semiconductor in modern electronics. It's known that, SiC has more than 200 polytypes. Cubic (3C - SiC) and hexagonal (4H and 6H) phase polytypes are most widely used between them in electronics system. Cubic modification nano SiC has more application potential in microelectronics due to the wide band gap (2.26eV), thermal and electrical properties [6-11]. Therefore, nano 3C-SiC (also known as  $\beta$ -SiC) particles with cubic modification have been used in all experiments in the given work.

The study of neutron irradiation effects to the physical and chemical properties of SiC, which is widely applied in fission - fusion reactor and electronics systems, is very important issue. The neutron flux influence on the lattice structure of 3C-SiC has been studied in the present work. Up to the present, in the large number of papers, it has been studied the effects of ionizing irradiation on SiC [12-19]. But the radiation effects on the lattice structure of these type materials have not been fully studied. Neutron irradiation formed defects and its lead to important changes in electro-physical properties of the samples [12-19]. First of all, *let us briefly consider* the defects formed in nanoparticles after neutron irradiation. 3C-SiC nanoparticles consist of Si and C atoms with cubic modification and high-energy recoils can be observed in primary knock-on atoms (PKA) within the neutron flux influence on lattice atoms [20-28]. Effects of ionizing radiation on nanocrystalline 3C-SiC particles are sparsely studied [24-28]. Energy exchange between PKA and other neighbor atoms, point defects or clusters are generated and they are the basis of fundamental defects. The defects formed under the influence of neutron flux, it can be migrating and they are a real place for storage any charge [20-28].

## 2. Experimental

Cubic modification silicon carbide (3C-SiC) nanoparticles have  $120 \text{ m}^2 \cdot \text{g}^{-1}$  specific surface area (SSA), 18nm particles size, 99+% purity and  $0.03 \text{ g} \cdot \text{cm}^{-3}$  (real density  $3.216 \text{ g} \cdot \text{cm}^{-3}$ ) density is used at the present experiments (US Research Nanomaterials, Inc., TX, USA). The samples have been irradiated at full power mode (250 kW) by neutron flux ( $2 \times 10^{13} \text{ n} \cdot \text{cm}^{-2} \cdot \text{s}^{-1}$ ) in central channel (channel A1) of TRIGA Mark II light water pool type research reactor in “Reactor Centre” of Institute Jozef Stefan (IJS) in the Ljubljana, Slovenia. The parameters of neutron flux at full power mode in the central channel are follows:  $5.107 \times 10^{12} \text{ n} \cdot \text{cm}^{-2} \cdot \text{s}^{-1}$  ( $1 \pm 0.0008$ ,  $E_n < 625 \text{ eV}$ ) for thermal neutrons,  $6.502 \times 10^{12} \text{ n} \cdot \text{cm}^{-2} \cdot \text{s}^{-1}$  ( $1 \pm 0.0008$ ,  $E_n \sim 625 \text{ eV} \div 0.1 \text{ MeV}$ ) for epithermal neutrons,  $7.585 \times 10^{12} \text{ n} \cdot \text{cm}^{-2} \cdot \text{s}^{-1}$  ( $1 \pm 0.0007$ ,  $E_n > 0.1 \text{ MeV}$ ) for fast neutrons and finally for all neutrons in central channel the flux density is  $1.920 \times 10^{13} \text{ n} \cdot \text{cm}^{-2} \cdot \text{s}^{-1}$  ( $1 \pm 0.0005$ ) [29-35].

Nano SiC powder filled to aluminium containers which have high purity in a special condition have been made appropriate to the channels of the reactor. At first this experimental sample has been irradiated for 5 minutes and activity analysis have been conducted. Then the other sample has been continuously irradiated for 20 hours by neutron flux ( $2 \times 10^{13} \text{ n} \cdot \text{cm}^{-2} \cdot \text{s}^{-1}$ ) at full power (250kW) in channel A1. The EDP analysis of non-irradiated and neutron irradiated nanocrystalline SiC powder were observed by transmission electron microscope (TEM, Jeol JEM-2010F, analytical transmission electron microscope is equipped with a scanning unit (ADF, BD STEM detectors), EDXS and EELS). To prepare the TEM specimen, the powdered samples named “SiC (0h)” and “SiC (20h)” were dispersed in acetone solution by ultrasonication. The solution was dropped on carbon coated Cu-carbon mesh, dried in vacuum dryer and transferred to TEM for further EDP analyses. SAED and EDP analysis of the samples were carried out with up to 200 kV accelerating voltage before and after neutron irradiation.

## 3. Results and Discussion

SAED analysis were conducted on small areas. The corresponding electron diffraction patterns (EDP), recorded over larger area containing particles, show well-defined diffraction rings composed from diffraction spots, indicating nanocrystalline nature of the particles. (Fig.1). EDP ring patterns were analyzed in Gatan’s Digital Micrograph software package.

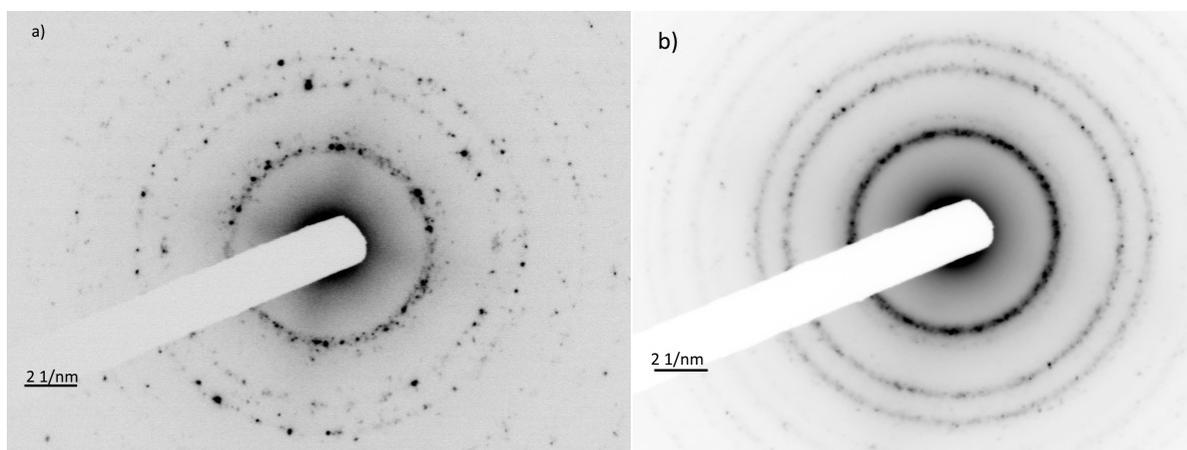


Fig. 1. EDP of nanocrystalline 3C-SiC particles before (a) and after (b) neutron radiation (recorded on agglomerated particles).

In both diffraction patterns (Fig.1) we performed rotational average (RA) analysis, which improves the resolution of the intensity profile. Such obtained patterns were merged together (Fig.2) and detailed comparison (Fig.3) show no significant difference in the position of the diffraction peaks, implying there was no influence of the neutron bombardment on the 3C-SiC crystal structure. Simultaneously, it can be concluded that some of the particles of irradiated sample may exhibit somewhat thicker amorphous layer surrounding the nanoparticle, however more analytical work (larger statistics) is needed to confirm this. It is assumed that this amorphous layer can be either the result of displacement of some lattice atoms or oxidation of some atoms on the surface as a result of neutron irradiation.

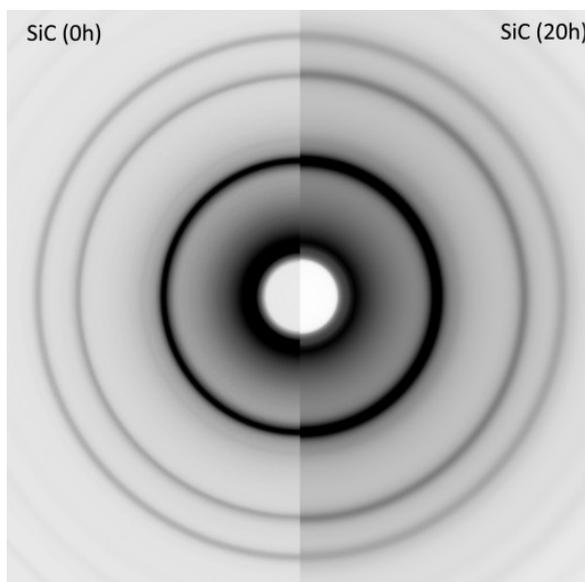


Fig. 2. Comparison of rotation average (RA) of EDPs between 3C-SiC (0h) and 3C-SiC (20h).

There were not any changes in comparative EDP analysis. And it allows us to say that radiation with neutron flux affects crystal structure of samples little or it doesn't affect. Moreover, comparative analysis of EDP d-values were conducted (Fig. 3).

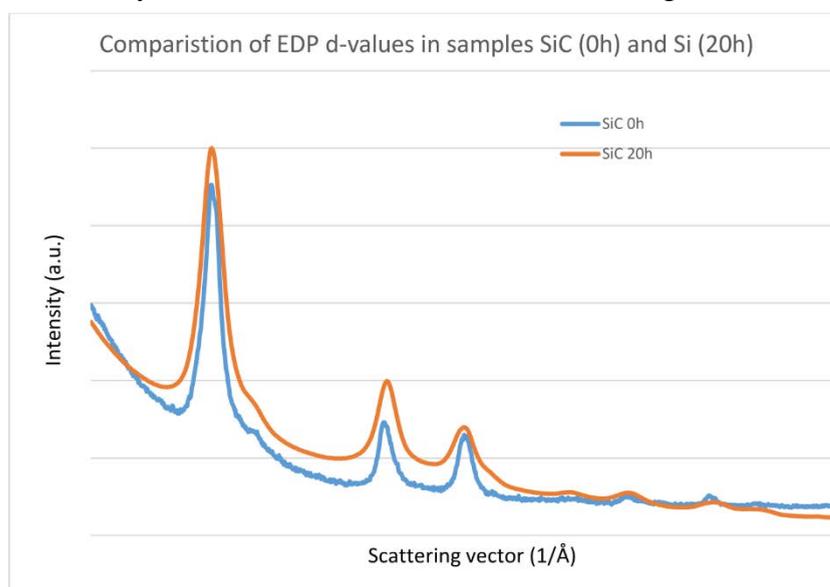


Fig. 3. Scattering vector ( $1/\text{\AA}$ ) of samples 3C-SiC (0h) and 3C-SiC (20h).

In the present work no difference at the peak positions between irradiated (orange) and nonirradiated samples (blue) (Fig 3), which implies that neutron bombardment did not influence the crystal structure of the 3C-SiC nanoparticles. And this once again approves the results obtained from comparative EDP analysis. However, one should consider that the measurements of  $d$  values using electron diffraction is inferior to the X-ray powder diffractions.

#### 4. Conclusions

It is clear from EDP analysis that nanocrystalline 3C-SiC particles have little amorphous transformation after neutron irradiation. Probably, after neutron irradiation there is thicker amorphous layer surrounding the 3C-SiC nanoparticles. Amorphous layer of the surfaces of nanoparticles can cause a greater or lesser agglomeration degree. As a result of EDP analysis it has been found out that, by a majority, neutron irradiation doesn't affect crystal structure of 3C-SiC nanoparticles (excluding small amorphous transformation).

#### Acknowledgments

I gratefully acknowledge the assistance of our colleagues from Institute of Radiation Problems of Azerbaijan National Academy of Sciences and "Reactor Infrastructure Centre (RIC)", "Nanostructured Materials K7", Centre for Electron Microscopy and Microanalysis at IJS. I would like to thank Prof. Dr. Luka Snoj and Anze Jazbec for providing irradiated samples in TRIGA Mark II type research reactor and Dr. Aljaz Ivekovic for encouraging discussions.

#### References

1. I. Vivaldo, M. Moreno, A. Torres et al. "A comparative study of amorphous silicon carbide and silicon rich oxide for light emission applications" *Journal of Luminescence* 190, 215-220, 2017
2. Yutai Katoh, Lance L. Snead, Izabela Szlufarska, William J. Weber "Radiation effects in SiC for nuclear structural applications" [Current Opinion in Solid State and Materials Science 16, 3, 2012, 143–152](#)
3. Jiyang Fan, Paul K. Chu "Silicon Carbide Nanostructures: Fabrication, Structure, and Properties" [ISBN 978-3-319-08726-9, Springer International Publishing Switzerland 2014](#)
4. Mohd Idzat Idris, Hiroshi Konishi, Masamitsu Imai et. al "Neutron Irradiation Swelling of SiC and SiCf/SiC for Advanced Nuclear Applications" [Energy Procedia 71, 2015, 328–336](#)
5. Narendra Singh, Kirandeep Singh, Davinder Kaur "Electric field involved transport at elevated temperature in nanocrystalline silicon carbide nitride (nc-SiCN) thin films for harsh environment applications" *Current Applied Physics* 18, 2, 220-225, 2018
6. Debopriyo Mallick, Omprakash Chakrabarti, Dipten Bhattacharya, Manabendra Mukherjee, Himadri S. Maiti and Rabindranath Majumdar "Electrical conductivity of cellular Si/SiC ceramic composites prepared from plant precursors" [Journal of Applied Physics 101, 033707, 2007](#)
7. Yang Zhonghua, Liu Guili, Qu Yingdong, Li Rongde "First-principle study on energy gap of CNT superlattice structure" [Journal of Semiconductors 36, 10, 2015](#)
8. Hui-wang Cui, Dong-sheng Li and Qiong Fan "Using Nano Hexagonal Boron Nitride Particles and Nano Cubic Silicon Carbide Particles to Improve the Thermal Conductivity of Electrically Conductive Adhesives" [Electronic Materials Letters 9, 1, 2013, 1-5](#)

9. ToanDinh, Dzung Viet Dao, Hoang-Phuong Phanet. al "Charge transport and activation energy of amorphous silicon carbide thin film on quartz at elevated temperature" [Applied Physics Express 8, 061303, 2015](#)
10. DOU Yan-Kun, QI Xin, JINHai-Bo, CAO Mao-Sheng, UsmanZahid, HOU Zhi-Ling "First Principle Study of the Electronic Properties of 3C-SiC Doped with Different Amounts of Ni" [Chinese Physics Letters 29, 7, 077701, 2012](#)
11. H. Xie, J. Wang, T. Xi and Y. Liu "Thermal Conductivity of Suspensions Containing Nanosized SiC Particles" [International Journal of Thermophysics 23, 2, 571-580 2002](#)
12. Lance L. Snead, Takashi Nozawa, YutaiKatoh, Thak-Sang Byun, Sosuke Kondo, David A. Petti "Handbook of SiC properties for fuel performance modeling" [Journal of Nuclear Materials 371 \(2007\) 329–377](#)
13. L.L. Snead "Limits on irradiation-induced thermal conductivity and electrical resistivity in silicon carbide materials" [Journal of Nuclear Materials 329–333 \(2004\) 524–529](#)
14. Bun Tsuchiya, Tatsuo Shikama, Shinji Nagata, Kesami Saito, Syunya Yamamoto, Seiki Ohnishi, Takashi Nozawa "Radiation induced changes in electrical conductivity of chemical vapor deposited silicon carbides under fast neutron and gamma-ray irradiations" [Fusion Engineering and Design 86 \(2011\) 2487–2490](#)
15. R. Scholz, F. dos Santos Marques, B. Riccardi "Electrical conductivity of silicon carbide composites and fibers" [Journal of Nuclear Materials 307–311 \(2002\) 1098–1101](#)
16. Y. Katoh, S. Kondo, L.L. Snead "DC electrical conductivity of silicon carbide ceramics and composites for flow channel insert applications" [Journal of Nuclear Materials 386–388 \(2009\) 639–642](#)
17. ManatoDeki, Takuto Ito, Minoru Yamamoto, Takuro Tomita, Shigeki Matsuo, Shuichi Hashimoto, Takahiro Kitada, Toshiro Isu, Shinobu Onoda, and Takeshi Ohshima "Enhancement of local electrical conductivities in SiC by femtosecond laser modification" [Applied Physics Letters 98, 133104, 2011](#)
18. V. V. Kozlovski, A. A. Lebedev, E. V. Bogdanova, N. V. Seredova "Effect of Irradiation with MeV Protons and Electrons on the Conductivity Compensation and Photoluminescence of Moderately Doped p-4H-SiC (CVD)" [Semiconductors, 2015, Vol. 49, No. 9, pp. 1163–1165](#)
19. E.R. Hodgson, M. Malo, J. Manzano, A. Morono, T. Hernandez "Radiation induced modification of electrical conductivity for three types of SiC" [Journal of Nuclear Materials 417 \(2011\) 421–424](#)
20. Y.Satoh, Y.Matsuda, T.Yoshiie, M.Kawai, H.Matsumura, H.Iwase, H.Abe, S.W.Kim, T.Matsunaga "Defect clusters formed from large collision cascades in fcc metals irradiated with spallation neutrons" [Journal of Nuclear Materials 442, S768–S772, \(2013\)](#)
21. M.L.Gamez, M.Velarde, F.Mota, J.Manuel Perlado, M.Leon, A.Ibarra "PKA energy spectra and primary damage identification in amorphous silica under different neutron energy spectra" [Journal of Nuclear Materials 367–370, pp. 282–285, \(2007\)](#)
22. R.Chakarova, I.Pazsit "Fluctuations and correlations in sputtering and defect generation in collision cascades in Si" [Nucl. Instrum. and Meth. B 164&165, 460 – 470 \(2000\)](#)
23. Harry J.Whitlow, Sachiko T.Nakagawa "Low-energy primary knock on atom damage distributions near MeV proton beams focused to nanometre dimensions" [Nuclear Instruments and Methods in Physics Research B 260 \(2007\) 468–473, 2007](#)
24. Elchin Huseynov, Anze Jazbec "Trace elements study of high purity nanocrystalline silicon carbide (3C-SiC) using k<sub>0</sub>-INAA method" *Physica B: Condensed Matter* 517, 30–34, 2017
25. Elchin M. Huseynov "Permittivity-frequency dependencies study of neutron-irradiated nanocrystalline silicon carbide (3C-SiC)" *NANO* 12, No. 6, 1750068, 2017

26. Elchin Huseynov "Effects of neutron flux on the temperature dependencies of permittivity of 3C-SiC nanoparticles" Silicon 9/5, 753–759, 2017
27. Elchin M. Huseynov "Investigation of the agglomeration and amorphous transformation effects of neutron irradiation on the nanocrystalline silicon carbide (3C-SiC) using TEM and SEM methods" Physica B: Condensed Matter 510, 99–103, 2017
28. Elchin Huseynov "Neutron irradiation and frequency effects on the electrical conductivity of nanocrystalline silicon carbide (3C-SiC)" Physics Letters A 380/38, 3086-3091, 2016
29. Dusan Calic, Gasper Zerovnik, Andrej Trkov, Luka Snoj "Validation of the Serpent 2 code on TRIGA Mark II benchmark experiments" [Applied Radiation and Isotopes 107, 165–170, 2016](#)
30. P. Filliatre, C. Jammes, L. Barbot, D. Fourmentel, B. Geslot, I. Lengar, A. Jazbec, L. Snoj, G. Žerovnik "Experimental assessment of the kinetic parameters of the JSI TRIGA reactor" [Annals of Nuclear Energy 83, 236–245, 2015](#)
31. Zerovnik, G et al. "Validation of the neutron and gamma fields in the JSI TRIGA reactor using in-core fission and ionization chambers" [Applied Radiation and Isotopes, 96, 27-35, 2015](#)
32. Henry R., Tiselj I., Snoj L. "Analysis of JSI TRIGA MARK II reactor physical parameters calculated with TRIPOLI and MCNP" [Applied Radiation and Isotopes, 97, 140-148, 2015](#)
33. Tanja Kaiba, Gasper Zerovnik, Anze Jazbec, Ziga Stancar, Loic Barbot, Damien Fourmentel, Luka Snoj "Validation of neutron flux redistribution factors in JSI TRIGA reactor due to control rod movements" [Applied Radiation and Isotopes 104, 34–42, 2015](#)
34. Kolsek A., Radulovic V., Trkov A., Snoj L. "Using TRIGA Mark II research reactor for irradiation with thermal neutrons" [Nuclear Engineering and Design, 283, 155–161, 2015](#)
35. Gasper Zerovnik, Manca Podvratnik, Luka Snoj "On normalization of fluxes and reaction rates in MCNP criticality calculations" [Ann. Nucl. Energy 63, 126–128, 2014](#)

## ИССЛЕДОВАНИЕ EDP КАРБИДА НАНОКРИСТАЛЛИЧЕСКОГО КРЕМНИЯ (3C-SiC) ПРИ НЕЙТРОННОМ ОБЛУЧЕНИИ

Э.М. Гусейнов

**Резюме:** В настоящей работе нанокристаллический карбид кремния (3C-SiC) облучен нейтронным потоком ( $\sim 2 \times 10^{13} \text{ n} \cdot \text{cm}^{-2} \cdot \text{s}^{-1}$ ) до 20 часов в разные периоды. Сравнительно проанализировано электронно-дифрактограммовое исследование (EDP) нанокристаллических частиц 3C-SiC ( $\sim 18$  нм) до и после нейтронного облучения. Влияние облучения на кристаллическую структуру наноматериала изучалось методом электронной дифракции области (SAED) и EDP. Аморфные трансформационные эффекты облучения нейтронами на карбиде нанокристаллического кремния (3C-SiC) изучены методом EDP.

**Ключевые слова:** нанокристаллический карбид кремния (3C-SiC), наночастицы, нейтронное облучение, ТЭМ

## NEYTRONLARLA ŞÜALANMANIN TƏSİRİ ALTINDA NANOKRISTALLIK SILISIUM KARBIDİN (3C-SiC) EDP TƏDQIQI

Е.М. Hüseynov

**Xülasə:** Təqdim olunan işdə nanokristallik silisium karbid (3C-SiC) neytron seli ilə ( $\sim 2 \times 10^{13} \text{ n} \cdot \text{cm}^{-2} \cdot \text{s}^{-1}$ ) fərqli müddətlərdə 20 saata qədər şüalandırılmışdır. Nanokristallik 3C-SiC hissəcikləri ( $\sim 18 \text{ nm}$ ) elektron

difraksiyası ilə şüalanmadan öncə və sonra müqaisəli analiz edilmişdir. Nanomaterialın kristal strukturda şüalanma effektləri seçilmiş sahədən elektron difraksiyası və EDP üsulları ilə öyrənilmişdir. Neytronlarla şüalanma nəticəsində nanokristallik silisium karbidin (3C-SiC) amorflaşma çevrilmələri EDP metodu ilə tədqiq edilmişdir.

**Açar sözlər:** nanokristallik silisium karbidin (3C-SiC), nanohissəciklər, neytron irradiyası, TEM.